

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S2	1	("6853873").PN.	US-PGPUB; USPAT	OR	OFF	2005/05/12 17:17
S4	294	(702/81).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 10:56
S6	163	(702/82).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 11:11
S7	95	(702/83).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 11:18
S8	294	(702/84).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 12:14
S9	460	(702/85).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 12:58
S10	548	(702/117).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:14
S11	113	(702/121).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:17
S12	215	(702/155).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:22
S13	110	(702/166).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:24
S14	168	(702/170).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:27
S15	71	(702/172).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:37
S16	919	(702/182).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/13 13:56
S17	765	(702/183).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 12:05
S18	297	(356/128).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 12:18
S19	444	(356/601).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 12:59
S20	109	(356/609).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 13:01
S21	97	(356/612).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 13:04
S22	88	(356/626).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 13:07
S23	395	(356/630).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 18:27
S24	217	(356/635).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 18:33
S25	342	(438/5).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/17 18:54
S26	354	(438/7).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:06
S27	1816	(438/14).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:26
S28	747	S27 and (optical (feed adj forward))	US-PGPUB; USPAT	OR	ON	2005/05/23 15:08
S29	842	(438/16).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 16:23
S30	529	(700/108).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 16:38
S31	263	(700/109).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 16:48
S32	353	(700/110).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 17:10
S33	1245	(700/121).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/05/23 17:10

S34	17	optical adj metrology and feed adj forward	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 11:52
S35	46	optical adj metrology and downstream	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:14
S37	0	(wafer microelectronic semiconductor) near (fabrication manufacture manufacturing) and feed adj foward	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:16
S38	227	(wafer microelectronic semiconductor) near (fabrication manufacture manufacturing) and downstream with (parameter measurement)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 11:59
S39	2	optical adj metrology and three adj dimensional adj characterization	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:28
S40	1	(wafer microelectronic semiconductor) near (fabrication manufacture manufacturing) and metrology same three adj dimensional adj characterization	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:17
S41	8	(wafer microelectronic semiconductor) near (fabrication manufacture manufacturing) and three adj dimensional adj characterization	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:17
S42	0	optical adj metrology and multiple adj wavelenghts	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:28
S43	1	optical adj metrology and wavelenghts	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:30
S44	113	optical adj metrology and spectrometer	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/05/24 12:30